

N-Channel MOSFET MEM2306

General Description

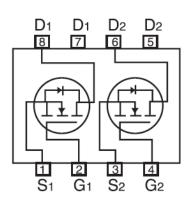
MEM2306SG Series Dual N-channel enhancement mode field-effect transistor produced with high cell density DMOS trench technology, which is especially used to minimize on-state resistance. This device particularly suits low voltage applications, and low power dissipation.

Features

- 20V/5A,
 - $R_{DS(ON)} = 29 \text{m}\Omega @ V_{GS} = 3.85 \text{V}, I_D = 5 \text{A}$
- High Density Cell Design For Ultra Low On-Resistance
- surface mount package: SOP8



Pin Configuration



Typical Application

- Battery management
- power management
- Portable equipment
- Low power DC to DC converter.
- Load switch
- LCD adapter

Absolute Maximum Ratings

| Parameter | | Symbol | Ratings | Unit |
|-------------------------------------|----------------------|------------------|---------------|----------------------|
| Drain-Source Voltage | | V_{DSS} | 20 | V |
| Gate-Source Voltage | | V_{GSS} | ±12 | V |
| Drain Current | T _A =25℃ | I _D | 5 | Α |
| Pulsed Drain Current ^{1,2} | | I _{DM} | 30 | Α |
| Total Power Dissipation | T _A =25℃ | Б | 1.3 | 10/ |
| | T _A =70°C | P_{D} | 1.0 | W |
| Operating Temperature Range | | T _{Opr} | 150 | $^{\circ}$ C |
| Storage Temperature Range | | T _{stg} | 65/150 | $^{\circ}\mathbb{C}$ |



Thermal Characteristics

| Parameter | | Symbol | Ratings | Unit |
|----------------------------------|--------------|------------------|---------|------|
| Thermal Resistance, | Stoody State | D | 62.5 | °C/W |
| Junction-to-Ambient ³ | Steady-State | R _{θJA} | 62.5 | C/VV |

Electrical Characteristics

| Parameter | Symbol | Test Condition | Min | Туре | Max | Unit | |
|--------------------------------------|---------------------|--|----------|------|------|------|--|
| | | Static Character | istics | | | | |
| Drain-Source Breakdown Voltage | $V_{(BR)DSS}$ | V _{GS} =0V, I _D =250μA | 20 | 23 | | V | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS},$ $I_{D}=250\mu A$ | 0.5 | 0.72 | 1 | V | |
| Gate-Body Leakage | I _{GSS} | $V_{DS}=0V$, $V_{GS}=12V$ | | 5 | 100 | nA | |
| | | V _{DS} =0V, V _{GS} =-12V | | -7 | -100 | nA | |
| Zero Gate Voltage Drain Current | I_{DSS} | V _{DS} =16V V _{GS} =0V | | 1.8 | 1000 | nA | |
| Static Drain-Source On-Resistance | R _{DS(ON)} | V _{GS} =4.5V,I _D =6A | | | 23 | mΩ | |
| | | V _{GS} =3.85V,I _D =5A | | | 25 | mΩ | |
| | | V _{GS} =2.5V,I _D =4A | | | 35 | mΩ | |
| Forward Transconductance | g _{FS} | $V_{DS} = 10 \text{ V}, I_{D} = 6A$ | 6 | 20 | | S | |
| Source-drain (diode forward) voltage | V_{SD} | V _{GS} =0V,I _S =1.5A | | 0.8 | 1 | V | |
| | | Dynamic Characte | ristics | | | | |
| Input Capacitance | Ciss | V 0.V | | 1120 | 1500 | | |
| Output Capacitance | Coss | $V_{DS} = 8 V$, | | 480 | 630 | - pF | |
| Reverse Transfer Capacitance | Crss | $V_{GS} = 0 V,$ f = 1 MHz | | 110 | 160 | | |
| | | Switching Characte | eristics | | | | |
| Turn-On Delay Time | td(on) | $V_{DD} = 10 \text{ V},$ $RL = 10\Omega$ | | 25 | 60 | | |
| Rise Time | tr | I _D =1 A, | | 60 | 140 | ns | |
| Turn-Off Delay Time | td(off) | $V_{GEN} = 4.5 \text{ V},$ | | 60 | 140 | | |
| Fall-Time | tf | Rg = 6 Ω | | 50 | 60 | | |
| Total Gate Charge | Qg | V _{DS} = 10 V, | | 47 | 60 | | |
| Gate-Source Charge | Qgs | $V_{GS} = 4.5 \text{ V},$ | | 6 | | nc | |
| Gate-Drain Charge | Qgd | I _D = 6 A | | 8 | | | |



Typical Performance Characteristics:

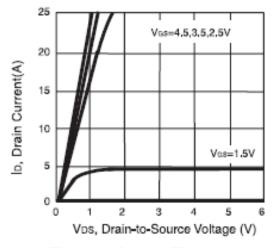


Figure 1. Output Characteristics

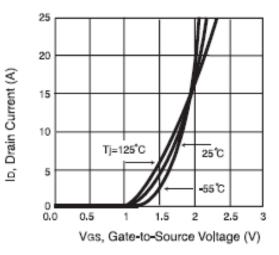
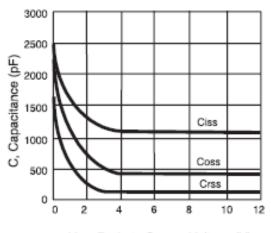


Figure 2. Transfer Characteristics



VDS, Drain-to Source Voltage (V)

Figure 4. On-Resistance Variation with Drain Current and Temperature



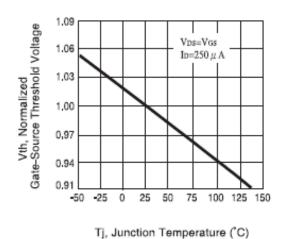
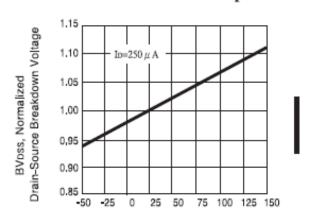


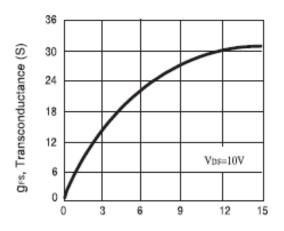
Figure 5. Gate Threshold Variation with Temperature



Tj, Junction Temperature (°C)

Figure 6. Breakdown Voltage Variation with Temperature





lps, Drain-Source Current (A)

Figure 7. Transconductance Variation with Drain Current

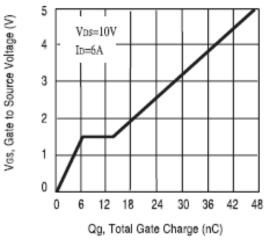


Figure 9. Gate Charge

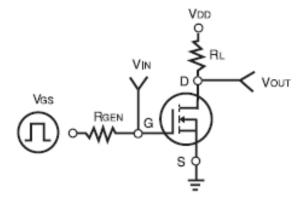
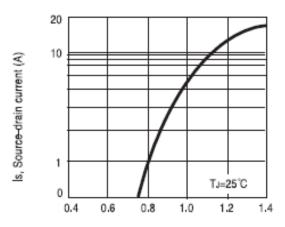


Figure 11. Switching Test Circuit



Vsp, Body Diode Forward Voltage (V)

Figure 8. Body Diode Forward Voltage Variation with Source Current

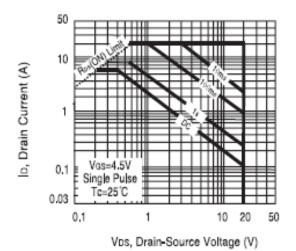


Figure 10. Maximum Safe Operating Area

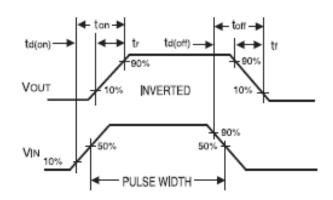


Figure 12. Switching Waveforms



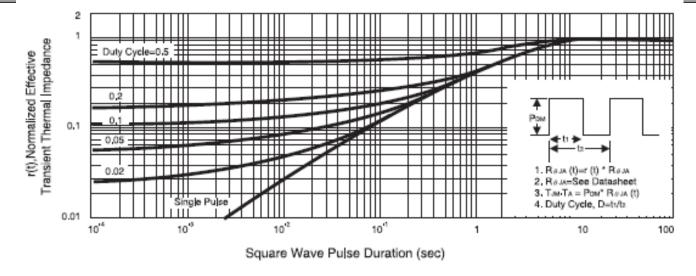
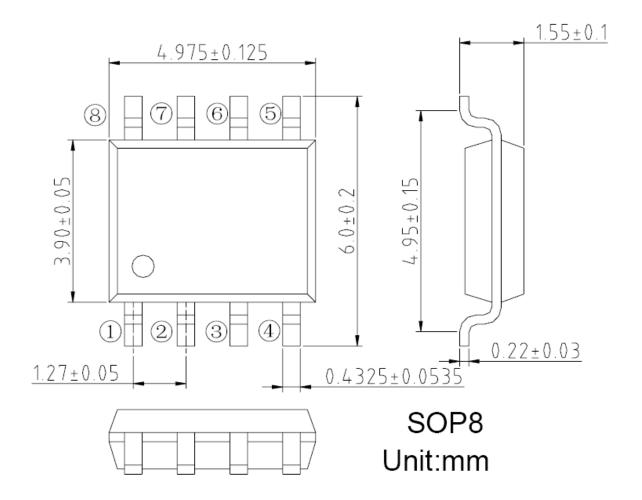


Figure 13. Normalized Thermal Transient Impedance Curve

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